
Surface chemical analysis — Electron spectroscopies — Procedures for identifying, estimating and correcting for unintended degradation by X-rays in a material undergoing analysis by X-ray photoelectron spectroscopy

*Analyse chimique des surfaces — Spectroscopie d'électrons —
Procédures pour l'identification, l'estimation et la correction de
la dégradation involontaire par rayons X pendant une analyse de
matériau par spectroscopie de photoélectrons par rayons X*





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